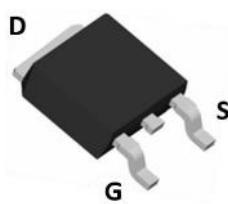


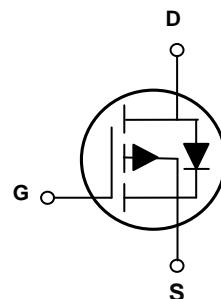
30V P-Channel MOSFET

Main Product Characteristics:

$V_{(BR)DSS}$	-30V
$R_{DS(ON)}$	7mΩ(max.)
I_D	-60A



TO-252



Schematic Diagram

Features and Benefits

- Standard Turbo MOSFET process technology.
- Optimized the cell structure.
- Low on-resistance and low gate charge.
- Featuring low switching and drive losses.
- Fast switching and reverse body recovery.
- High ruggedness and robustness.



Description

The ST series products utilizes Trust's outstanding standard turbo process and packaging techniques to achieve ultra low on-resistance and low gate charge and to provide the industry's best-in-class performance.

These features make this series products extremely efficient, temperature characteristics and reliable for use in power management, synchronous rectification, battery protection, load switch and a wide variety of other applications.

Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Max.	Unit
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous ($T_c=25^\circ\text{C}$), $V_{GS}=10\text{V}^1$	I_D	-60	A
Drain Current-Continuous ($T_c=100^\circ\text{C}$), $V_{GS}=10\text{V}^1$		-45	A
Drain Current-Pulsed ²	I_{DM}	-240	A
Pulsed Source Current (Body Diode) ²	I_{SM}	-240	A
Maximum Power Dissipation ($T_c=25^\circ\text{C}$) ³	P_D	70	W
Single Pulse Avalanche Energy ($L=0.3\text{mH}$)	E_{AS}	289	mJ
Single Pulse Avalanche Current ($L=0.3\text{mH}$)	I_{AS}	41	A
Junction-to-Ambient ($t \leq 10\text{s}$) ⁴	$R_{\theta JA}$	62	$^\circ\text{C}/\text{W}$
Maximum Junction-to-Case ⁵	$R_{\theta JC}$	1.79	$^\circ\text{C}/\text{W}$
Operating Junction Temperature Range	T_J	-55 To +150	$^\circ\text{C}$
Storage Temperature Range	T_{STG}	-55 To +150	$^\circ\text{C}$



30V P-Channel MOSFET

Electrical Characteristics ($T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-30	-	-	V
Drain-to-Source Leakage Current	$I_{\text{DS}}^{\text{SS}}$	$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-1	μA
Drain-to-Source Leakage Current		$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V} T_J=125^\circ\text{C}$	-	-	-50	μA
Gate-to-Source Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
On Characteristics						
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{GS}}=V_{\text{DS}}, I_{\text{D}}=-250\mu\text{A}$	-1.0	-1.6	-3	V
Drain Static-Source On-Resistance	$R_{\text{DS(ON)}}$	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-20\text{A}$	-	5.4	7	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-15\text{A}$	-	8.7	9.7	$\text{m}\Omega$
Dynamic and Switching Characteristics						
Total Gate Charge	Q_g	$V_{\text{DD}}=-15\text{V}, I_{\text{D}}=-20\text{A}$ $V_{\text{GS}}=-10\text{V}$	-	61	-	nC
Gate-Source Charge	Q_{gs}		-	7.6	-	
Gate-Drain Charge	Q_{gd}		-	15.2	-	
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}}=-15\text{V}, R_G=3\Omega$ $R_L=0.75\Omega$, $V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-20\text{A}$	-	21	-	nS
Rise Time	t_r		-	18	-	
Turn-Off Delay Time	$t_{\text{d(off)}}$		-	26	-	
Fall Time	t_f		-	8.2	-	
Input Capacitance	C_{iss}	$V_{\text{DS}}=-15\text{V}, V_{\text{GS}}=0\text{V},$ $F=1\text{MHz}$	-	3230	-	pF
Output Capacitance	C_{oss}		-	370	-	
Reverse Transfer Capacitance	C_{rss}		-	230	-	
Gate Resistance	R_g	$F=1\text{MHz}$	-	3.5	-	Ω
Source-Drain Ratings and Characteristics						
Maximum Body-Diode Continuous Current	I_s	MOSFET symbol showing the integral reverse p-n junction diode.	-	-60	-	A
Maximum Body-Diode Pulse Current	I_{sm}		-	-240	-	A
Diode Forward Voltage	V_{SD}	$V_{\text{GS}}=0\text{V}, I_{\text{s}}=-10\text{A}, T_J=25^\circ\text{C}$	-	-0.85	-1.2	V
Reverse Recovery Time	t_{rr}	$I_F=-20\text{A}$ $di/dt=100\text{A}/\mu\text{s}$ $T_J=25^\circ\text{C}$	-	15.1	-	nS
Reverse Recovery Charge	Q_{rr}		-	20.5	-	nC

Notes:

1. Calculated continuous current based on maximum allowable junction temperature.
2. Repetitive rating; pulse width limited by max. junction temperature.
3. The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
4. The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$

30V P-Channel MOSFET

Typical Electrical and Thermal Characteristic Curves

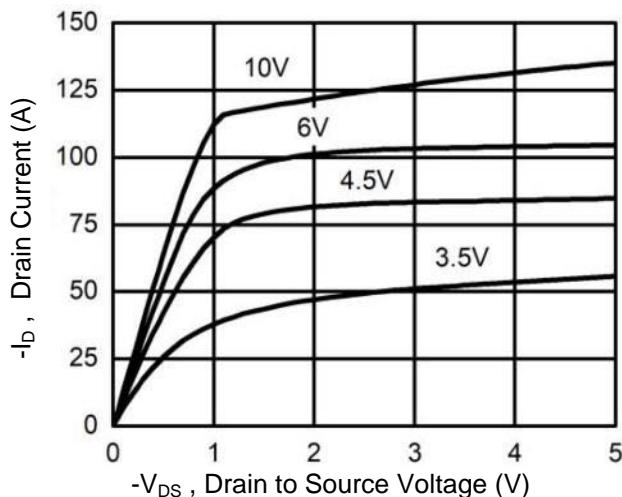


Fig.1 Typical Output Characteristics

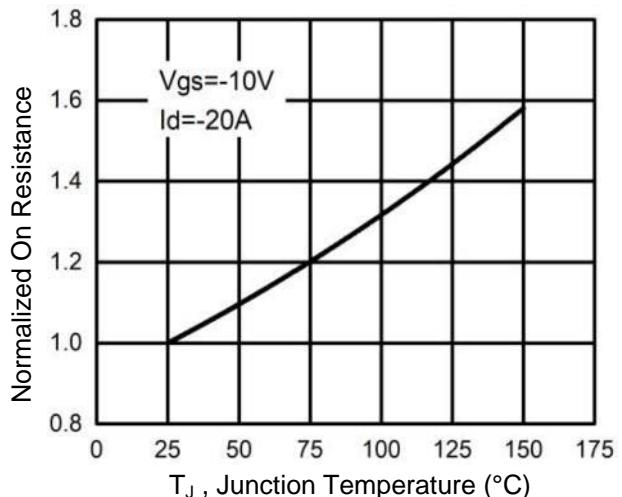


Fig.2 Normalized $R_{DS(ON)}$ vs. T_J

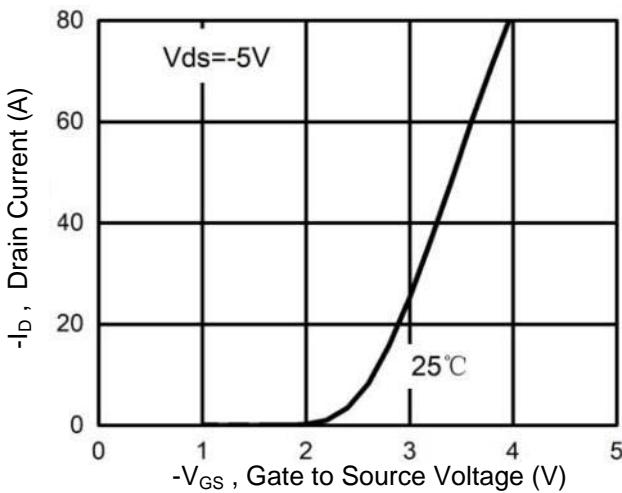


Fig.3 Typical Transfer Characteristics

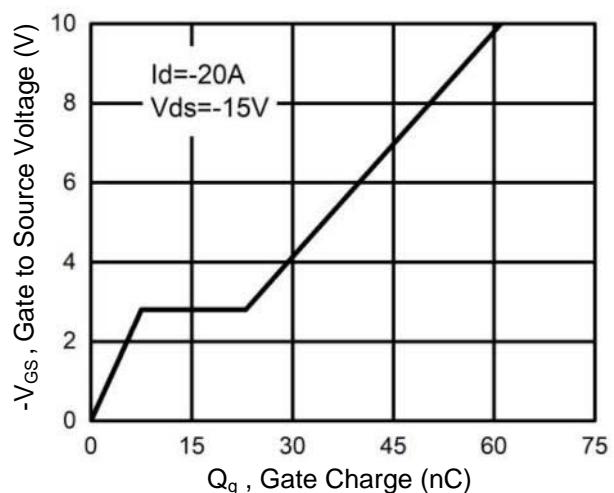


Fig.4 Gate Charge Waveform

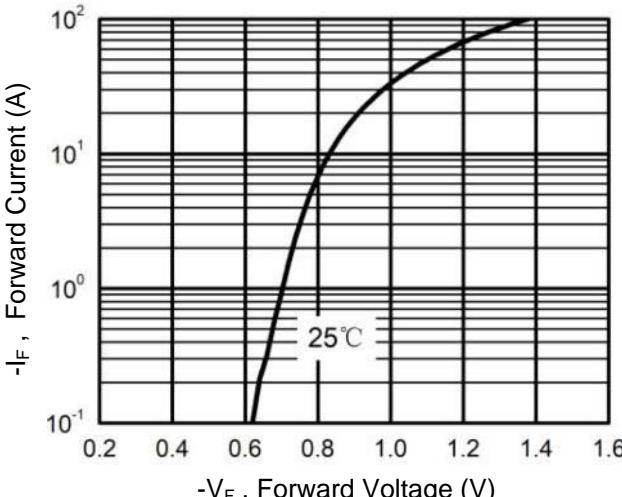


Fig.5 Typical Transfer Characteristics

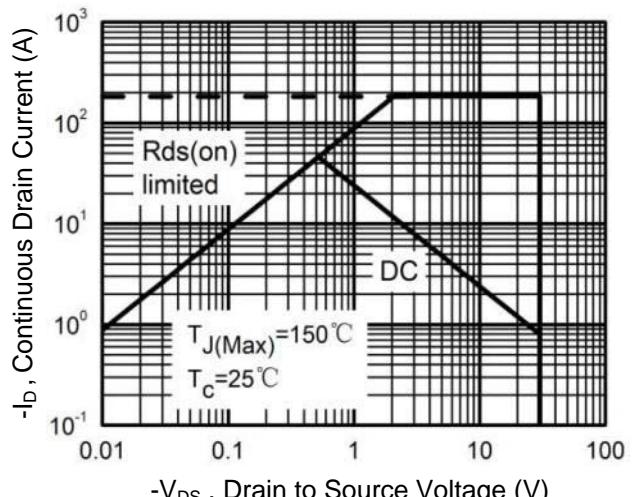


Fig.6 Maximum Safe Operation Area

30V P-Channel MOSFET

Test Circuits and Waveforms

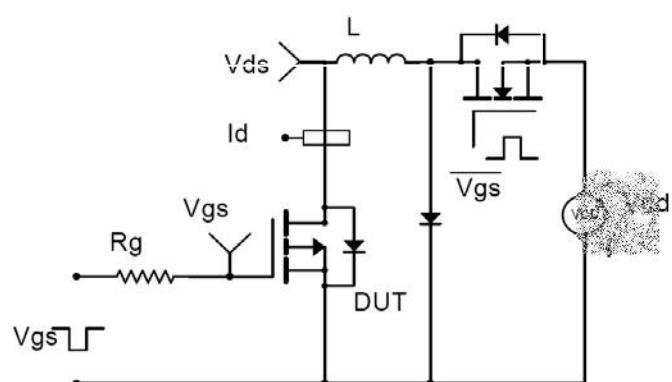


Figure 7. EAS Test Circuit

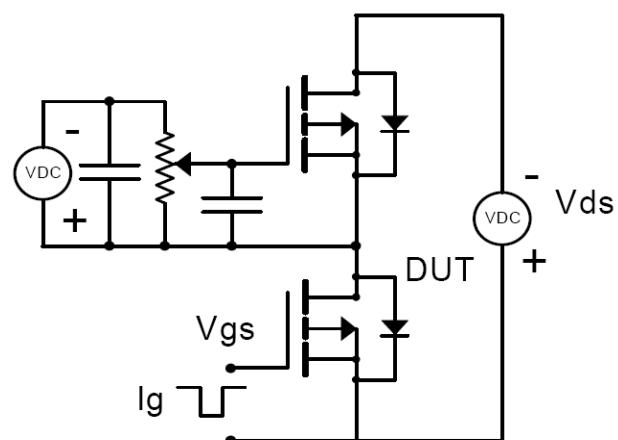


Figure 8. Gate Charge Test Circuit

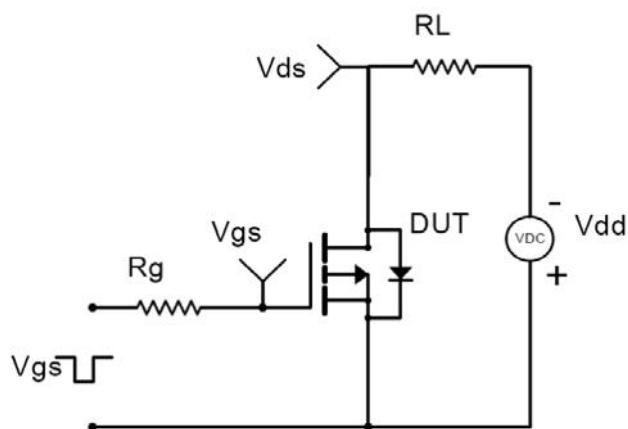


Figure 9. Switching Time Test Circuit

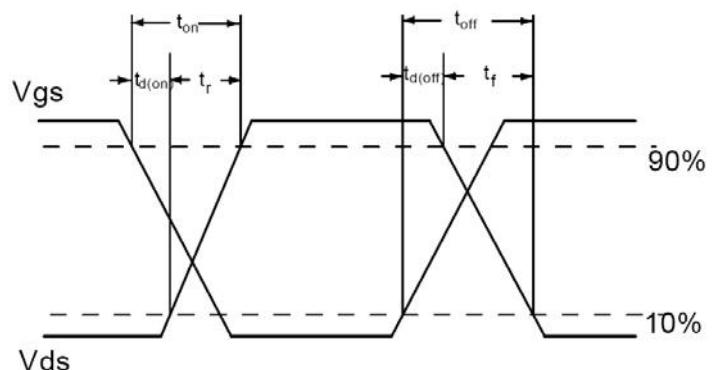
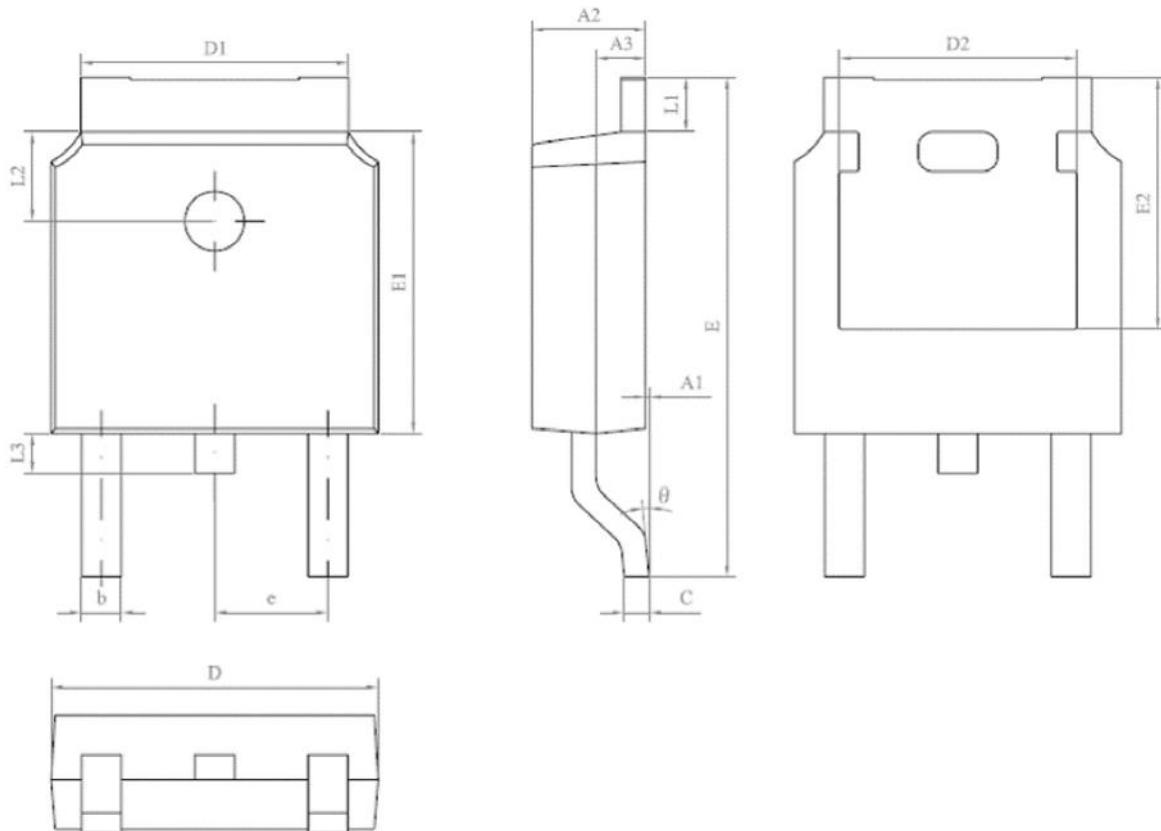


Figure 10. Switching Waveforms

30V P-Channel MOSFET

Package Outline Dimensions (TO-252/DPAK)



Symbol	Dimensions In Millimeters		Symbol	Dimensions In Millimeters	
	MAX	MIN		MAX	MIN
A1	0.10	0.00	E	10.30	9.90
A2	2.40	2.20	E1	6.20	6.00
A3	1.10	0.09	E2	5.20	5.00
b	0.85	0.75	e	2.20	2.40
C	0.60	0.50	L1	1.25	0.90
D	6.70	6.50	L2	1.90	1.70
D1	5.50	5.30	L3	1.00	0.60
D2	4.90	4.70	θ	8°	0°